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# Strain engineering of diamond microstructures by trench filling & oxidation

Presented by

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# Motivation: Why Diamond



**Diamond is the “Mount Everest” of the electronic, photonic, & quantum materials** [Dang et al., *Science*, 2021]

- Ultra wide bandgap
- Ultrahigh thermal conductivity
- High carrier mobility
- Ultrahigh dielectric breakdown strength
- Hosts color centers and quantum emitters

Diamond as a semiconductor

Property	Units	Si	GaAs	4H-SiC	GaN	AlN	Ga <sub>2</sub> O <sub>3</sub>	Diamond
<b>Bandgap</b>	eV	1.1	1.43	3.23	3.4	6	4.9	5.5
<b>Saturated drift velocity</b>	10 <sup>7</sup> cm/s	1	1	2.1	1.4	1.3	1.1	2.3
<b>Electron mobility</b>	cm <sup>2</sup> /V-s	1,240	4,167	980	1,000	426	153	7,300
<b>Hole mobility</b>	cm <sup>2</sup> /V-s	480	400	120	11			5,300
<b>Breakdown field</b>	MV/cm	0.3	0.4	3.1	4.95	15.4	10.3	13
<b>Thermal conductivity</b>	W/cm-K	1.45	0.55	3.7	2.53	3.19	0.22	22.9

→ 20 [Kurinsky, *PRD*, 2019]

Lincoln Laboratory, MIT (<https://www.evolvediamonds.com/electronic-properties-of-diamond>)

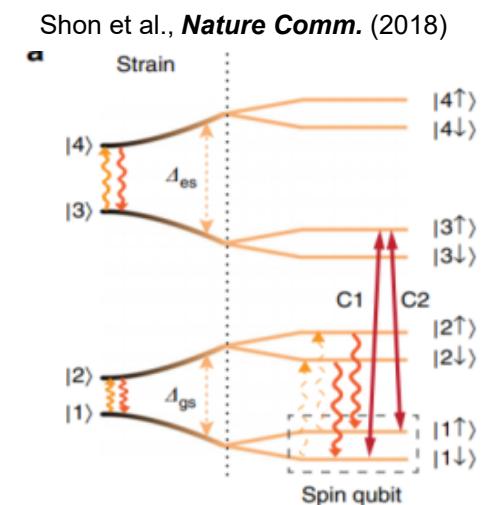
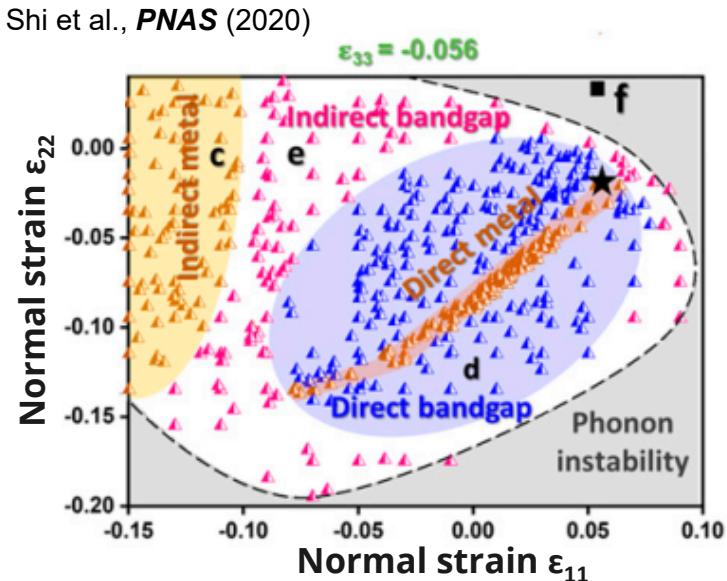
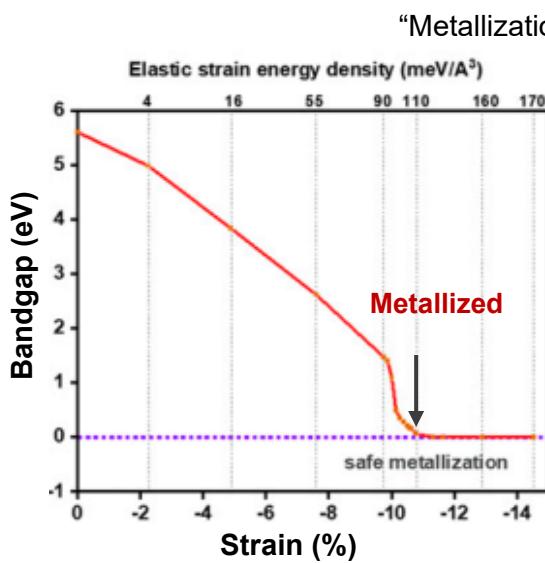
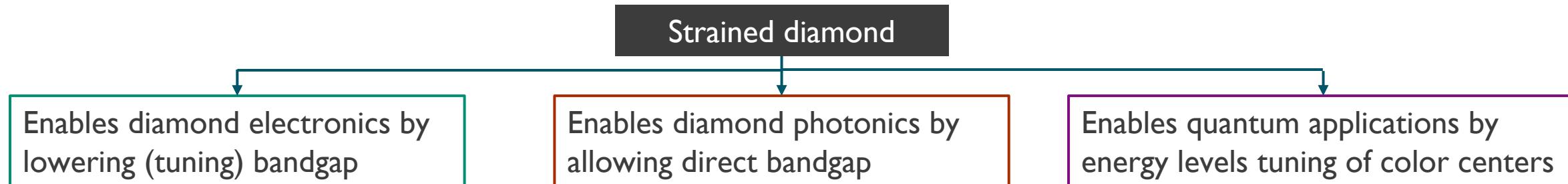
## Key challenges for the diamond applications

- Diamond electronics: challenging to dope, deep dopant levels (0.3 eV for B & 0.57 eV for P) [J. Tsao et al, *Adv. Electron. Mater.*, 2018]
- Diamond photonics: indirect bandgap
- Diamond quantum applications: difficult to control color center's energy levels and spin states

# Strained Diamond: Why do we care



## Strained diamond can be a solution for the outstanding challenges in diamond applications



Strain engineering of diamond creates new possibilities: high power electronics, efficient light emitters, on-diamond quantum sensors, and control of N-V, Si-V single photon emitters.

# Past Approaches

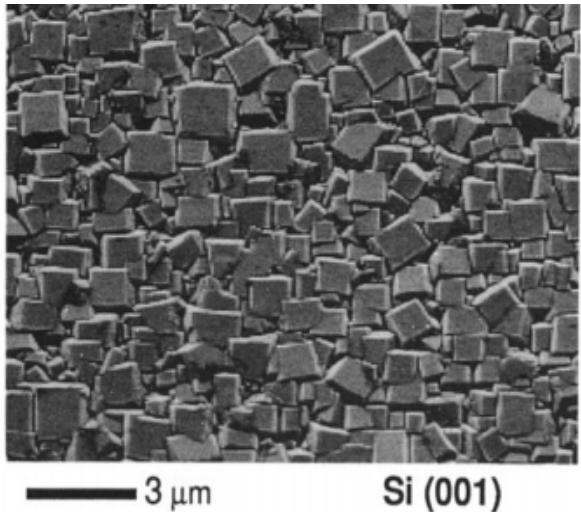


## Attempts of straining diamond by epitaxial growth (diamond film on substrate)

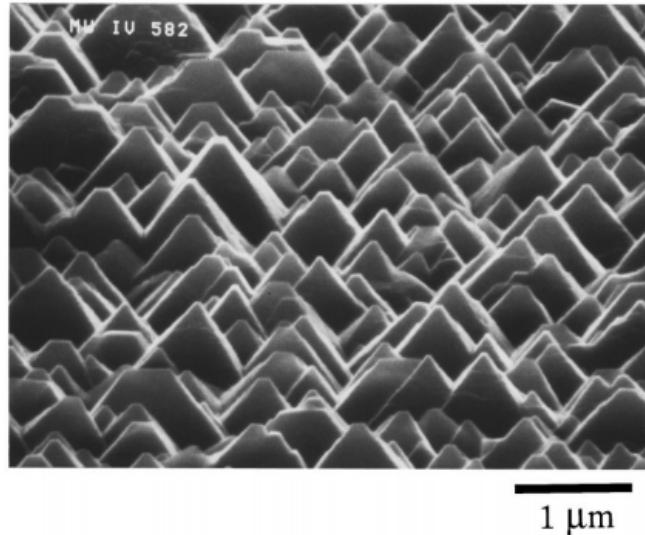
- Past 3 decades of attempt in heteroepitaxy on various substrates: Si<sup>1,2</sup>, SiC<sup>3</sup>, SiN<sub>x</sub><sup>4</sup>, GaN<sup>5</sup>, AlN<sup>6</sup>, & Ir<sup>7</sup> substrates
- All of these growths resulted polycrystalline film (mostly due to huge lattice mismatch, ~52% in Si), strain is relaxed
- So far, single crystal diamond has been reported on ~3% of growth region of Ir substrate with strain ~0.5%<sup>7</sup>

Nearly impossible to strain diamond by epitaxial growth!

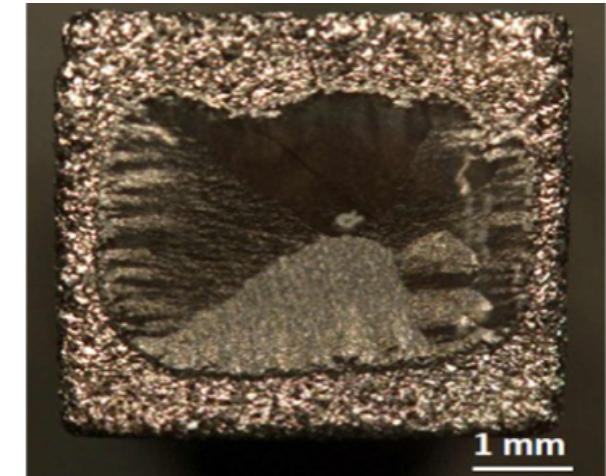
Si substrate<sup>2</sup>



SiC substrate<sup>3</sup>



Ir substrate<sup>7</sup>

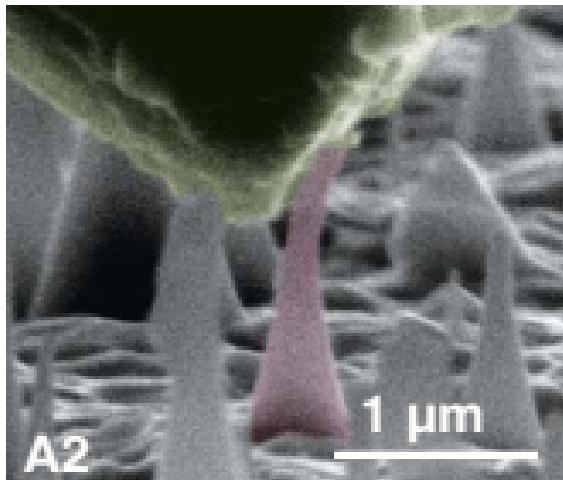


# Past Approaches

## Utilization of external forces

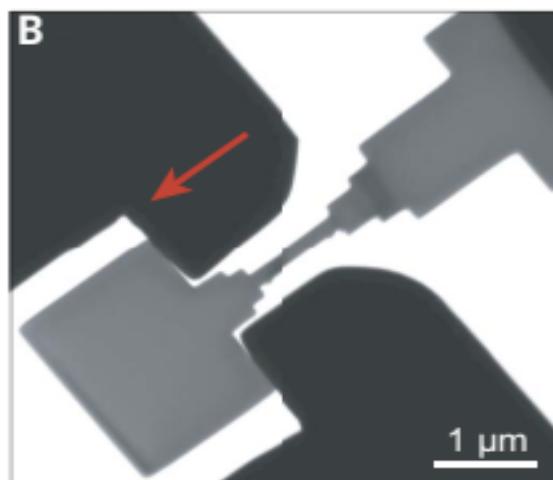
- Mechanical forces (bend/pull): demonstrated strain up to 9% without graphitization.
- Electrostatic forces: tunable strain with strain magnitude <0.02%

Banerjee et al. *Science* (2018)

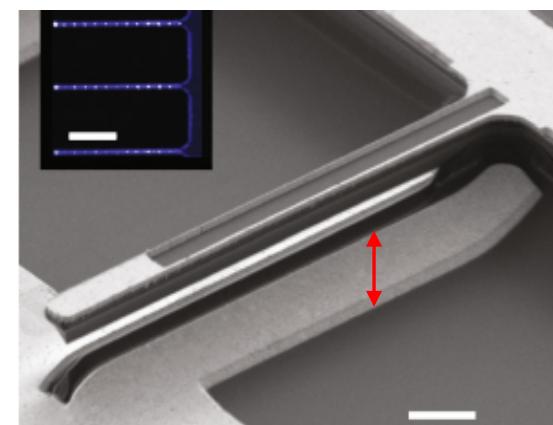


**Mechanical:** up to ~9% strain (no graphitization)

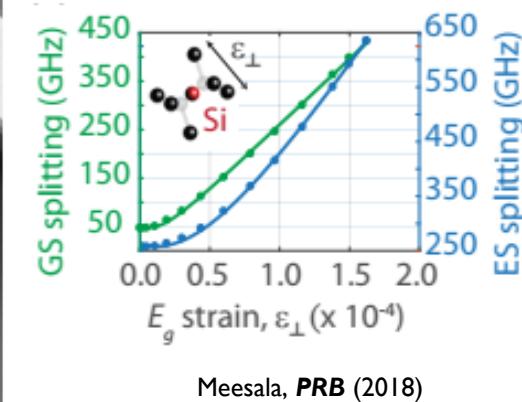
Dang et al., *Science* (2021)



Shon et al., *Nature Comm.* (2018)



**Electrostatic:** <0.02% strain



Meesala, *PRB* (2018)

**These approaches use external force to strain diamond; unscalable, temporary, & unfeasible for applications**

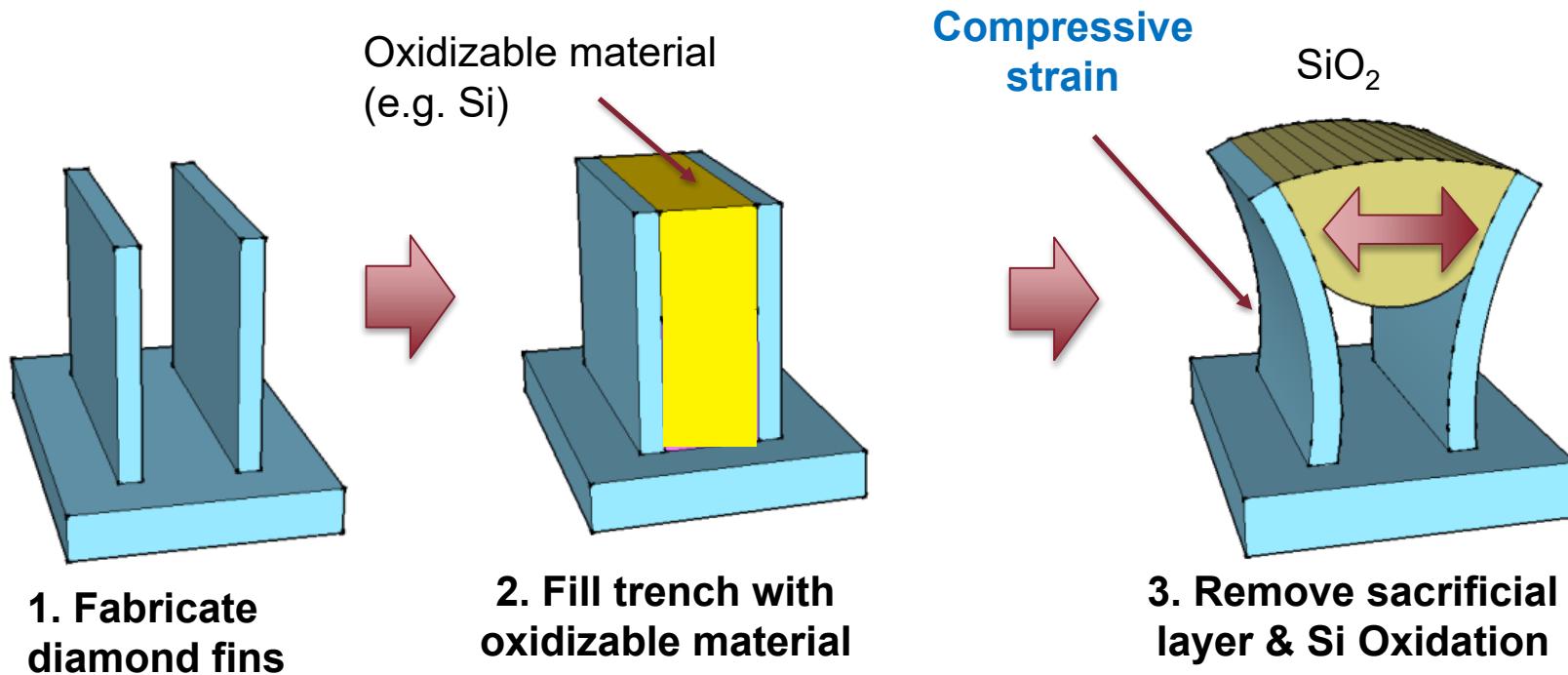
# Novel, on-chip, scalable approach of diamond straining



## Straining diamond microstructure by trench filled volume expansion (TFVE)

Straining diamond by TFVE:

- Fabrication of diamond fins
- Growth of oxidizable material (Si, Al) on diamond trench followed by oxidation
- Oxidation (e.g. Si to  $\text{SiO}_2$ ) → Volume expansion (volume increases 2.17 times)

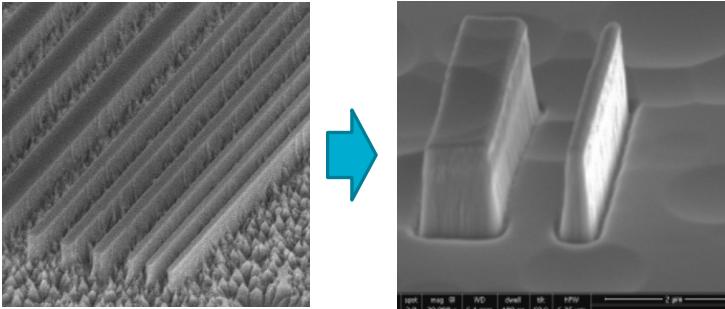


# Fabrication of diamond fins and trench filling



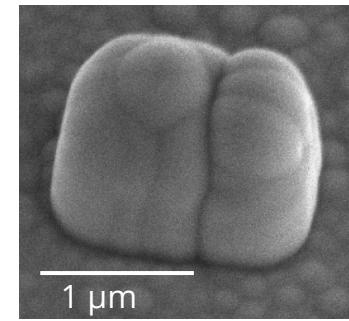
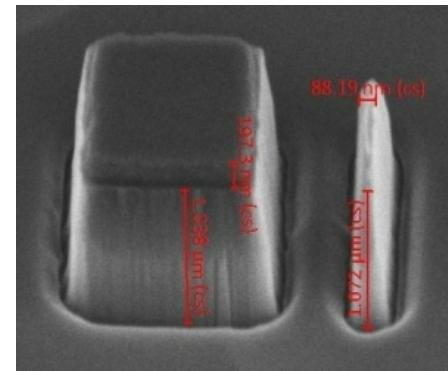
- Fabricated diamond fins using EBL patterned Ti mask and plasma etching
- Explored various methods to fill trench using Si and Al

## Diamond Nanofabrication

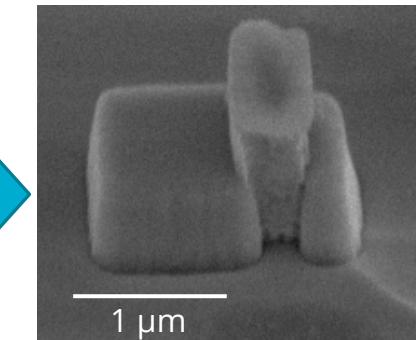


- Diamond etching: high density O<sub>2</sub> plasma etch (ICP/RIE)
- Crystal plane selective etch rate gives grassy structure at low RIE power
- Mask: Si<sub>3</sub>N<sub>4</sub>, SiO<sub>2</sub>, or metal mask (e.g. Ti) are good choice due to high selectivity.

## Trench filling and post fab



Poly-Si CVD growth.  
**Successful**

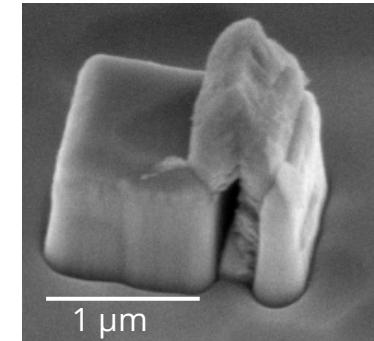


Post process to remove Si except from trench



## **Diamond Fin fabrication**

- 100nm to 250nm wide thin fins
- Trench gaps 500nm and 1μm



Evaporated Al filling of trench and oxidation



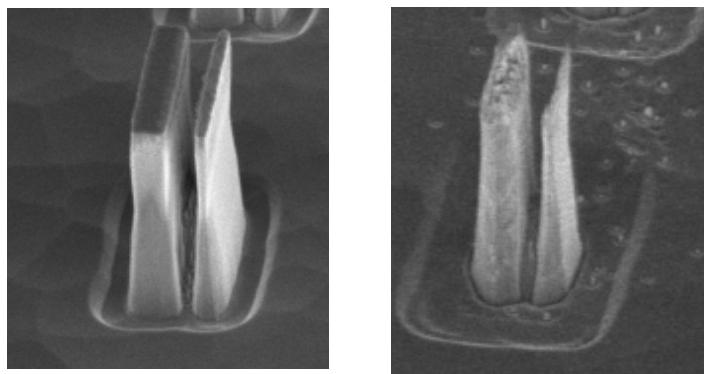
**Dry oxidation carried out at various temperatures**



# Trench oxidation

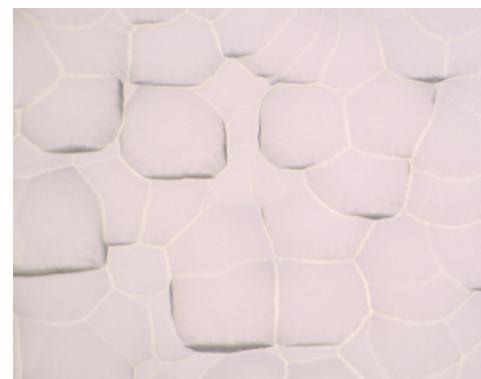
- Dry oxidation carried out at various temperatures
- Oxidation also impacts diamond: systematic study was carried out to understand the damage done on diamond during oxidation

Diamond oxidation tolerance test

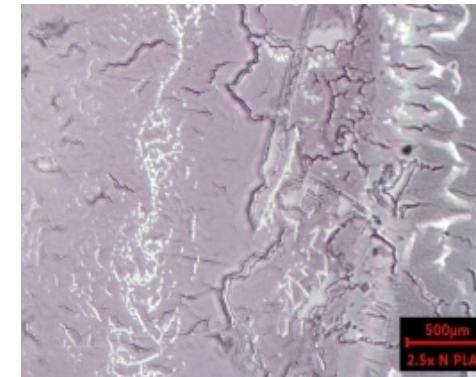


Before oxidation

Oxidation at 700 °C



Oxidation at 800 °C



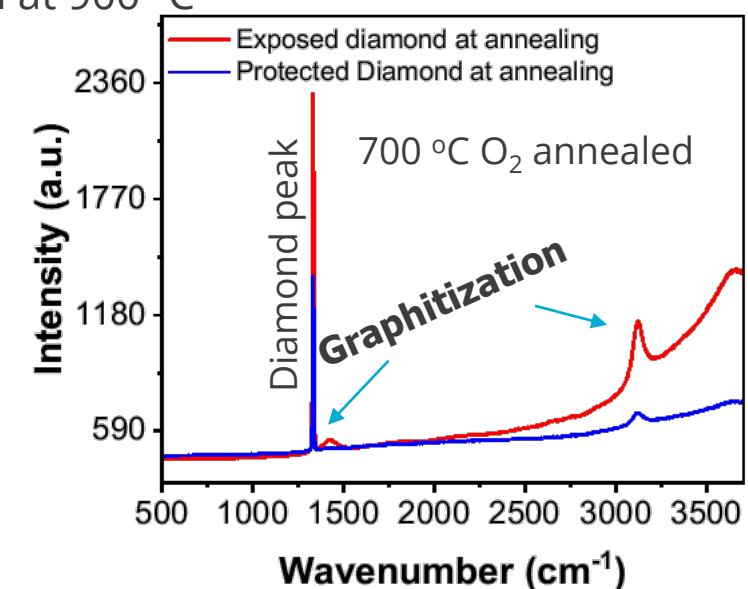
Oxidation at 900 °C

## Protection of diamond from oxidation degradation

- Diamond substrate coated all faces with ALD deposited  $\text{Al}_2\text{O}_3$  layer
- Systematically investigated the degradation at various oxidation temperature by Raman spectroscopy (*Manuscript Under preparation*)

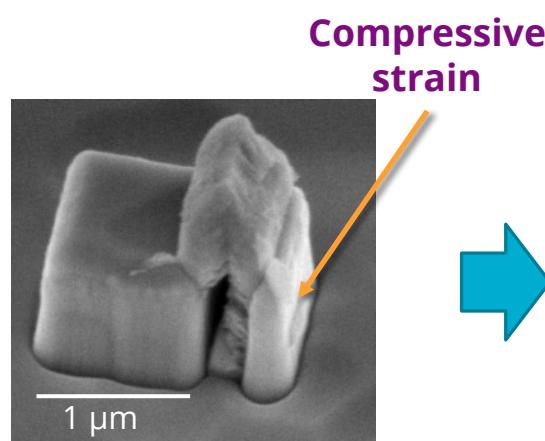
## Finding

- Diamond is well protected to optimal quality during oxidation by ALD - $\text{Al}_2\text{O}_3$  coating below 800 °C



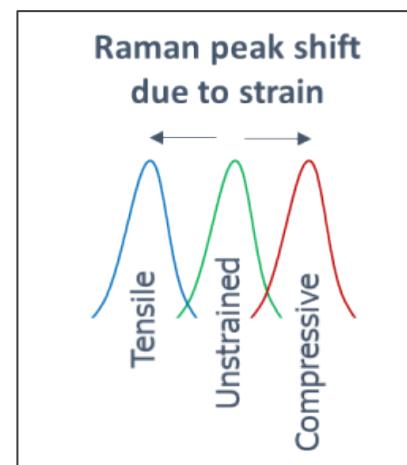
# Stress measurement in Al filled trench

- Stress on the diamond fins were investigated by Raman spectroscopy
- 2D Raman scans with 532nm laser, spot resolution 250nm

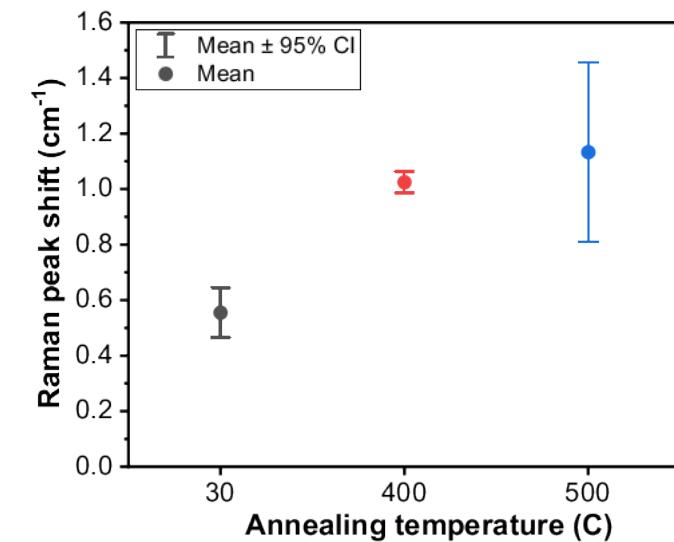
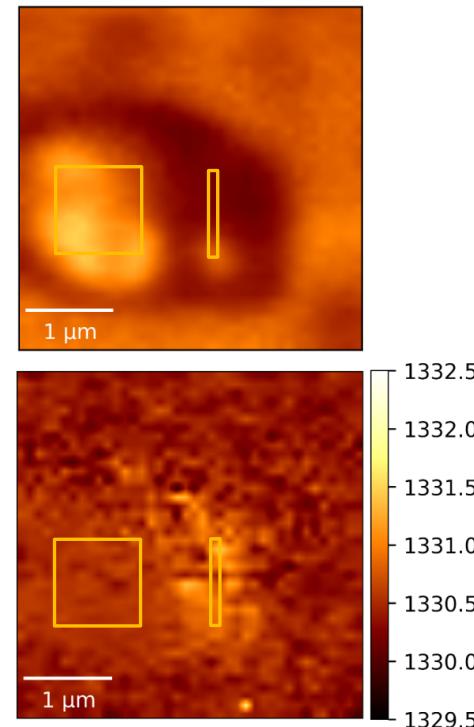


Evaporated Al filling of trench and oxidation

$$P = 0.34 \frac{GPa}{cm^{-1}} \Delta\nu$$



500 °C oxidation (Al filling)

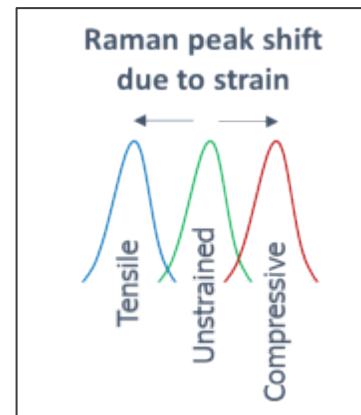
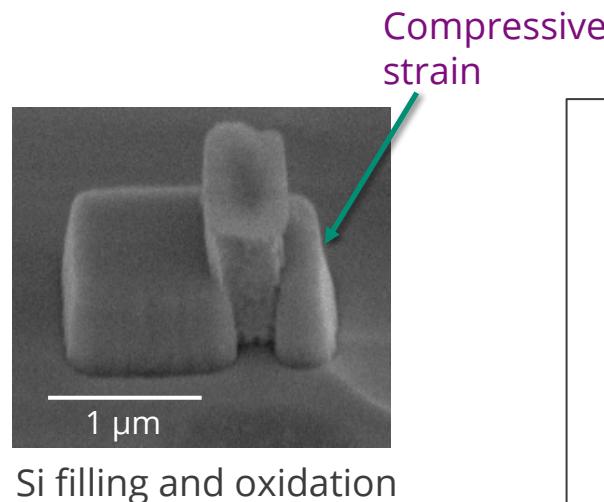


Peak shift due to compressive strain on Al filled trench  
*(Manuscript under preparation)*

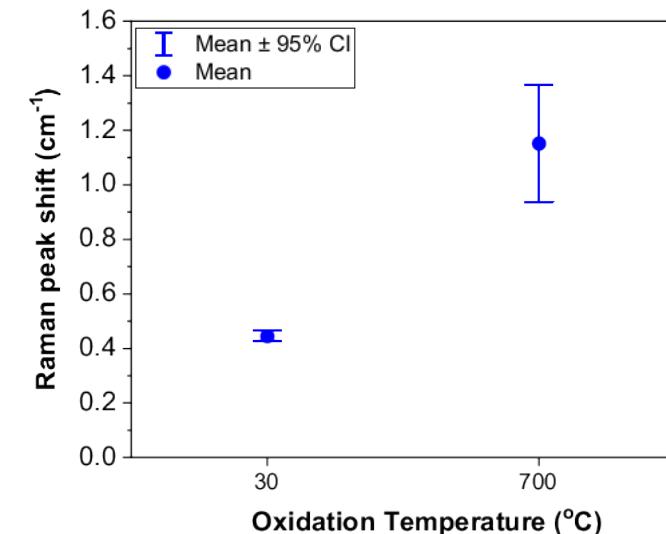
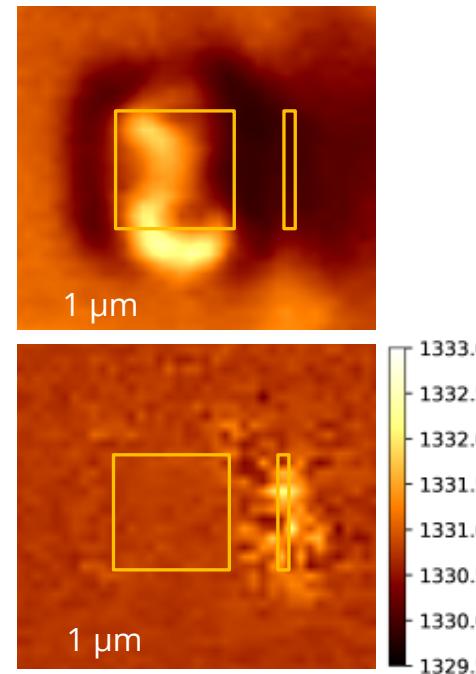
- Observed shift of Raman peaks to higher wave number in the thin fin region → **Compressive strain**
- Corresponding stress was in the range of 100s of MPa

# Stress measurement in Si filled trench

- Stress on the diamond fins were investigated by Raman spectroscopy
- 2D Raman scans with 532nm laser, spot resolution 250nm



700 °C oxidation (Si filled trench)



(Manuscript under preparation)

Raman peaks to higher wave number in the thin fin region → Compressive strain

Successfully demonstrated novel approach to strain diamond by trench filling and oxidation

# Summary



- Diamond is the 'Mount Everest' of electronic, photonic, and quantum materials due to its outstanding properties: UWBG, ultrahigh thermal conductivity, ultrahigh dielectric breakdown strength, high carrier mobility, and hosts of quantum emitters
- Strained diamond can enable bandgap tuning, conversion to direct bandgap, and tuning of energy level of quantum emitters
- Past attempts to strain diamond are either largely failed (e.g. epitaxial growth approach) or limited and unscalable due to use of temporary external forces
- Novel, on-chip, scalable approach of strain engineering of diamond nano/microstructures was investigated by trench filling and oxidation
- Pairs of diamond fins were fabricated by O-plasma etch and the trench between the fins pair was filled by oxidizable materials (e.g. Si, Al)
- Trench filled material was oxidized at various temperatures and the stress on the fins were investigated with Raman spectroscopy
- Raman peak shift to higher wave number was observed on the thin fin conforming compressive strain on the fin wall